

FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #20324D-C

Generic Copy

Issue Date: 24-Sep-2014

<u>TITLE</u>: Assembly and Test site transfer from Kanto Sanyo Semiconductors Co., Ltd to ON Semiconductor SSMP Philippines Corporation (Group 05-C)

PROPOSED FIRST SHIP DATE: 31-Dec-2014 (or earlier upon approval due to shortage of product)

AFFECTED CHANGE CATEGORY(S): Assembly and Test site

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or

- <toshiitsu.igarashi@onsemi.com><takeshi2.hoshino@onsemi.com> <shinya.okada@onsemi.com>
- <ikuo.saeki@onsemi.com><Toshimitsu.Namiki@onsemi.com><naoki.koyama@onsemi.com>
- <takehito.tsukui@onsemi.com> <keiji.ueda@onsemi.com>

SAMPLES: Contact your local ON Semiconductor Sales Office or <jun.hasunuma@onsemi.com>

ADDITIONAL RELIABILITY DATA: Available

Contact your local ON Semiconductor Sales Office or

<Takashi.Naruse@onsemi.com><Satoru.Fujinuma@onsemi.com>

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

As a part of restructuring of semiconductor production infrastructure, Hanyu plant of Kanto Sanyo Semiconductors Co., Ltd was closed at the end of June, 2014 and have been started preparation for end of production.

In order to continue supply of applicable products under this condition, the products and the equipments is transferring to ON Semiconductor SSMP Philippines Corporation.

The materials and package outline of these products will remain identical. Qualification tests are designed to show that the reliability of transferred devices will continue to meet or exceed ON Semiconductor standards.

Issue Date: 24-Sep-2014 Rev. 06-Jan-2010 Page 1 of 2



FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #20324D-C

RELIABILITY DATA SUMMARY:

Package name: UCT16

| Test Items | Test Condition | Test Time | Results |
|---|--|-----------|---------|
| Temperature Humidity Bias * | Ta=85degC,RH=85%, Vcc=Recommended | 1000hrs | Pass |
| Temperature Humidity Storage * | Ta=85degC,RH=85% | 1000hrs | Pass |
| Temperature Cycle * | Ta=-65degC(30min) ⇔ Ta=150degC (30min) | 100cycles | Pass |
| Pressure Cooker * | Ta=121degC,RH=100% ,205kPa | 100hrs | Pass |
| High Temperature Storage | Ta=150degC | 1000hrs | Pass |
| Resistance to Soldering heat (Reflow Soldering) | 255degC,10s (Peak260degC) | 2times | Pass |
| Solderability | 245degC,3s(with Flux) Soldering area,95% over(Sn-3.0Ag-0.5Cu) | 1time | Pass |

Notes:

Judgment Criteria:

Judgment Criteria are due to the limits of the electrical characteristics in the detail specification. (Except for Solderability)

ELECTRICAL CHARACTERISTIC SUMMARY:

There is no change in the electrical performance. Datasheet specifications remain unchanged.

CHANGED PART IDENTIFICATION:

Products manufactured at SSMP will be marked with 'L7' preceding the Serial No. on shipping label.

List of affected General Parts:

LV8081GQ-E

Issue Date: 24-Sep-2014 Rev. 06-Jan-2010 Page 2 of 2

The test items with * mark are put into operation after the reflow soldering (at 255degC for 10seconds) -> SMD

Temperature Humidity Bias Test: PD>=0.1W -> Intermittent power application consists of 1h ON and 3h OFF.